

A close-up, high-angle photograph of a microchip or semiconductor device. The chip is a complex network of fine, golden-brown lines (interconnects) and various colored rectangular regions (die, pads, or components) on a light-colored substrate. The lighting is warm, creating a golden glow across the entire scene. The background is slightly blurred, emphasizing the intricate details of the chip's surface.

CORNING

Advancements in Glass for Packaging Technology

17 Mar 2016

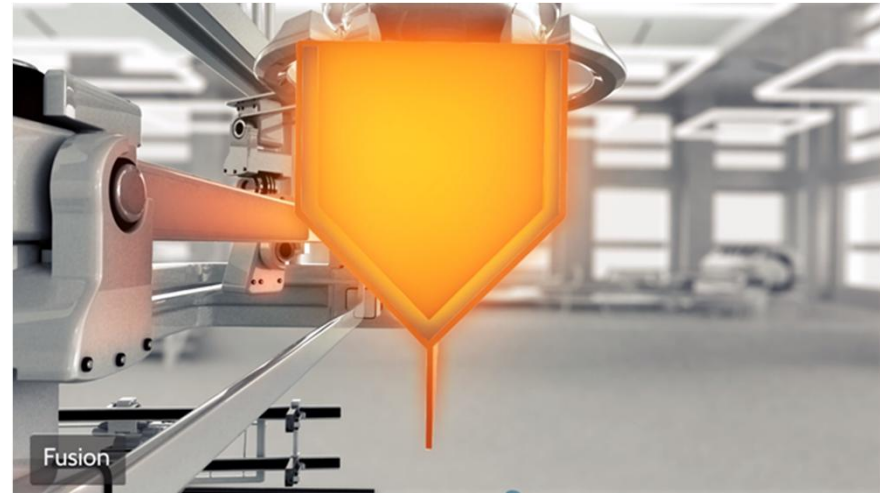
Kevin M. Adriance
Product Line Manager
Semiconductor Glass Products
Corning Incorporated

Our precision glass offers many attributes that are attractive for semiconductor applications...

Precision Glass

Corning's advanced **fusion** forming and **innovative glass compositions** provide:

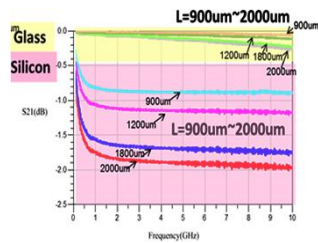
- Adjustable **CTE** offerings to meet various process requirements
- Profoundly **flat**
- **Scalable** with an ability to provide a wide variety of sizes and offerings: 100 mm to 450 mm
- **As-formed** surface
- Optical and transparency properties enabling visible **inspection** and other **light-based processing techniques**
- Excellent **chemical durability**
- Reusable



Corning's proprietary fusion manufacturing process is at the core of its innovation, providing precision glass that is smooth, flat, and dimensionally stable from millimeters thick to microns thin.

...and translate into meaningful value for our customers

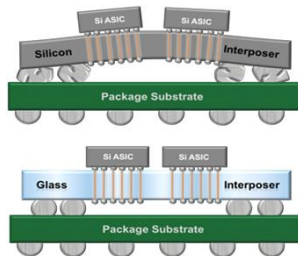
Electrical Properties



Low Electrical Loss

- Improved signal isolation
- Lower insertion loss = less power or longer battery life

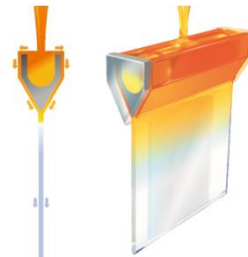
CTE Adjustability



Capability to deliver multiple CTEs

- Improves reliability
- Offer range of CTEs from 2.7-12.4

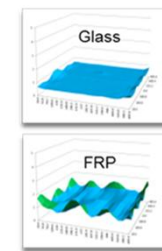
Surface Quality



Enables fine line spacing

- Smaller package size
- Fewer metal layers, resulting in cost savings

Stiffness



Glass is stiffer compared to organics

- Better flatness enables fine line spacing

Form Factor



Forming at thickness + panels

- Better yield/cost
- Better quality and efficiency in panels

Corning offers TGV with precision holes; product attributes are a good fit for both RF and interposer applications

Precision Holes

Glass Size:

Wafers: 100mm → 300mm

Panels: > 500x500 mm

Thickness:

~100 μ m → 700 μ m

Type of Holes:

Blind-Holes, Thru-Holes

Pattern:

Customer X,Y Location

Aspect Ratio:

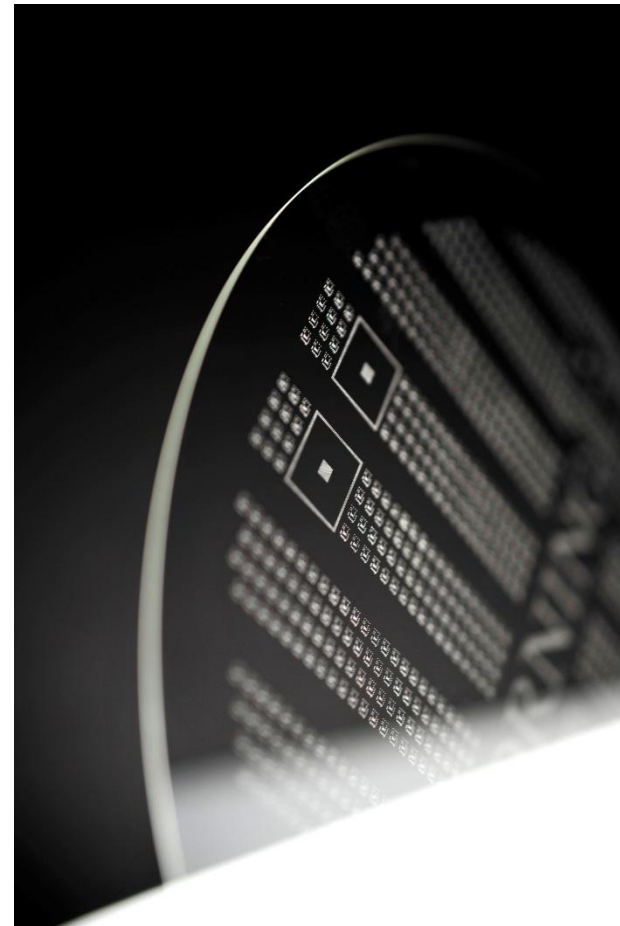
~3-10:1
(in part dictated by metal)

Pitch:

Minimum 2x Hole Diameter

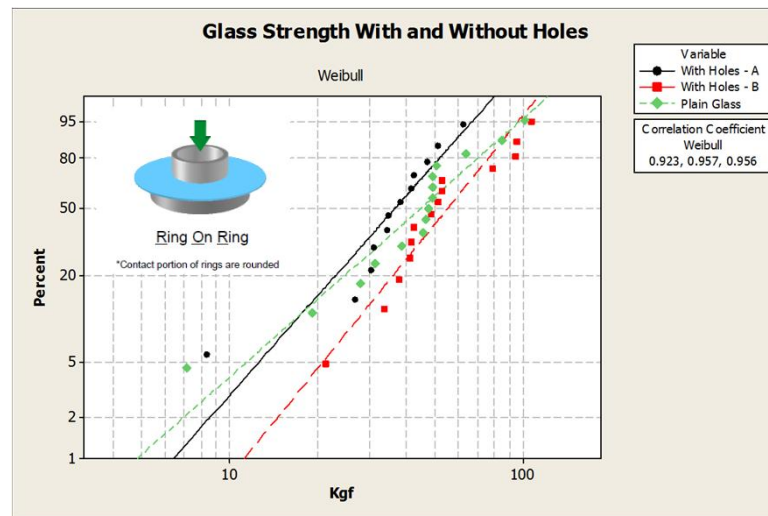
Hole Diameter:

100 μ m → 20 μ m → 10 μ m

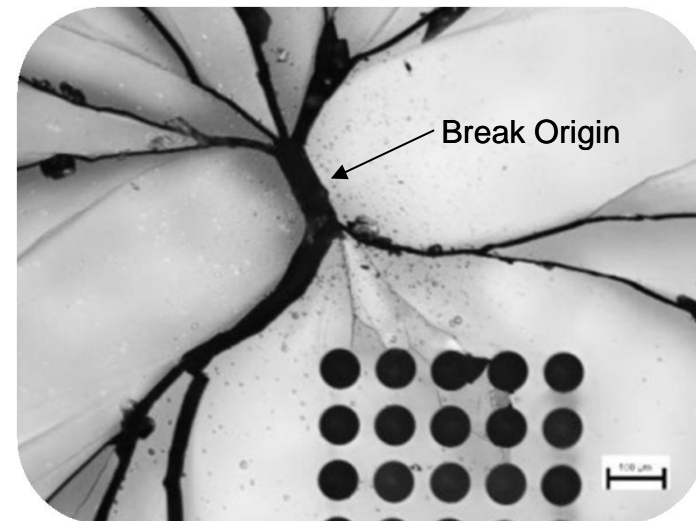


Our glass maintains strength throughout TGV process

Corning's advanced hole fabrication process retains the inherent strength of the glass substrate



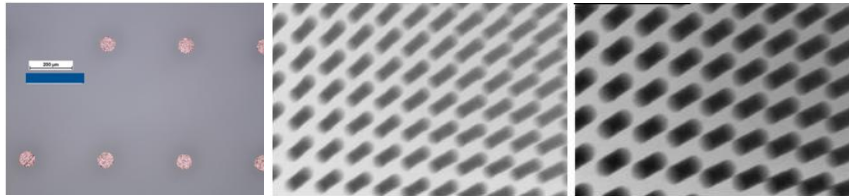
Ring on ring results for glass samples with and without holes. The strength of glass with holes brackets the strength of glass without holes.



Picture of ROR broken glass sample with 5x5 via array. Note that breakage did not originate at via array.

Demonstrated successful metallization of glass vias with several industry partners and are working on real projects

Paste Filling



Paste filled
TGV 30 μ m via
100 μ m thick

60 μ m via
void free
300 μ m thick glass

80 μ m via
void free
300 μ m thick
glass

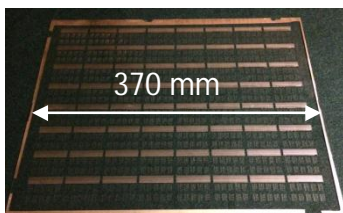


Sample Projects

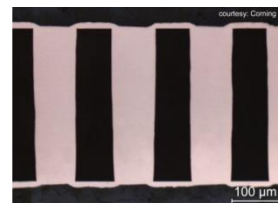


Dai Nippon Printing Co., Ltd.

Panel Processing



<3 μ m L/S 370x470mm
(130 μ m thick) with
~100,000 holes

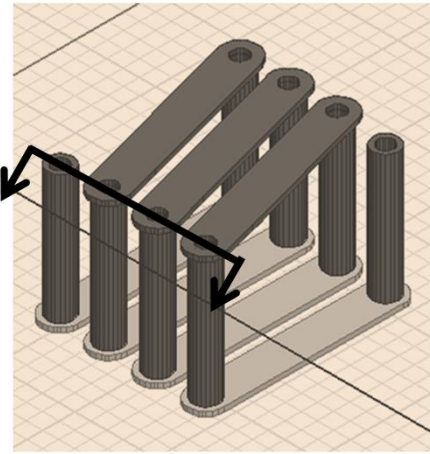


Atotech's double side
plating process can fill
through holes in panel
format with low
overburden

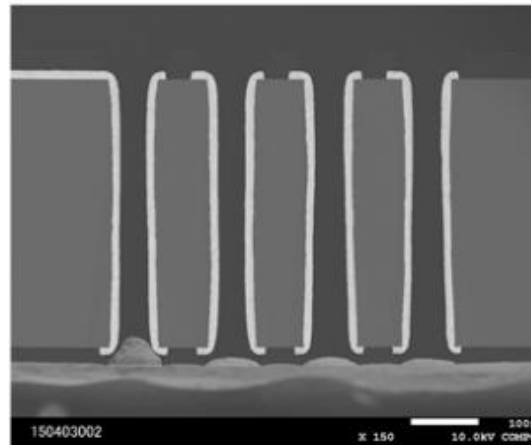


- TGV for RF Applications
- Low Cost Glass Interposer
- General Purpose Glass Modules

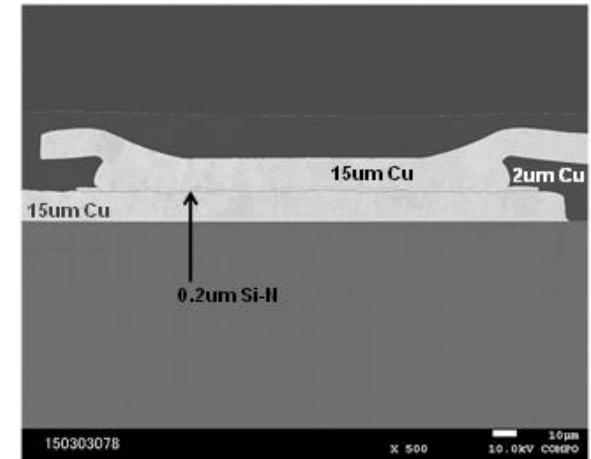
High Q inductor/capacitor prototypes demonstrated in conjunction with QCOM and DNP



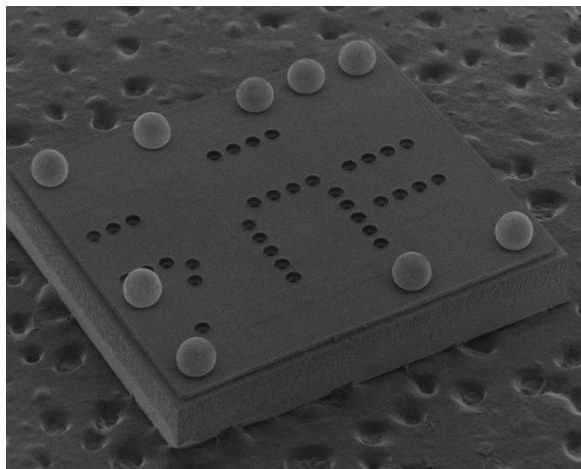
3D rendering of inductor structure, top-down view



Cross-sectional SEM of a fabricated 3D inductor

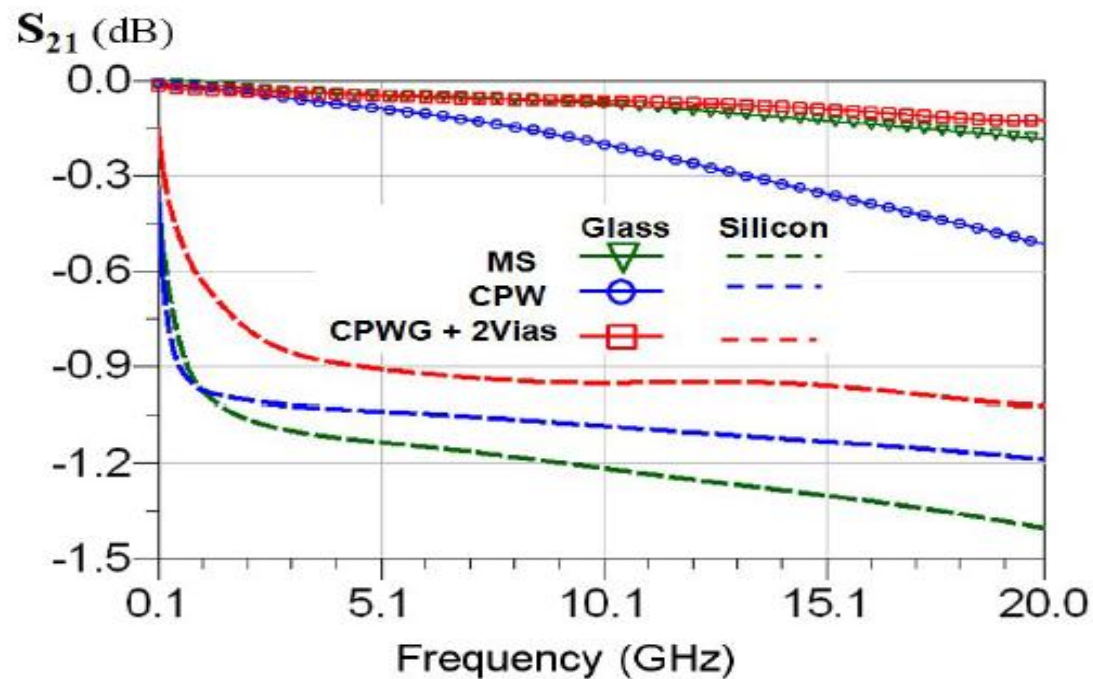
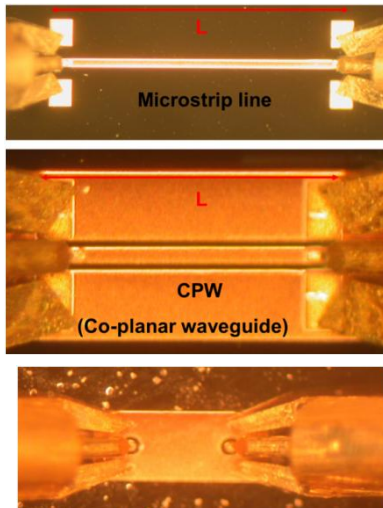
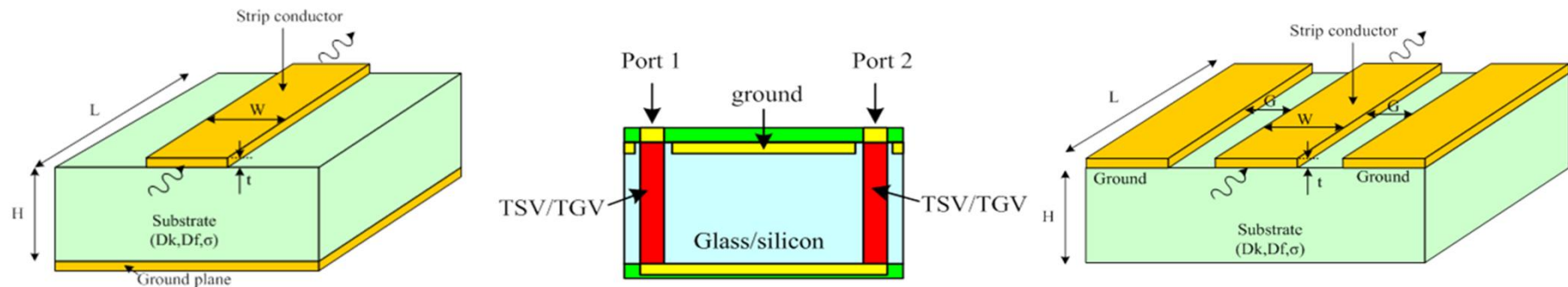


Cross-Sectional SEM of Cu-Silicon Nitride-Cu MIM structure

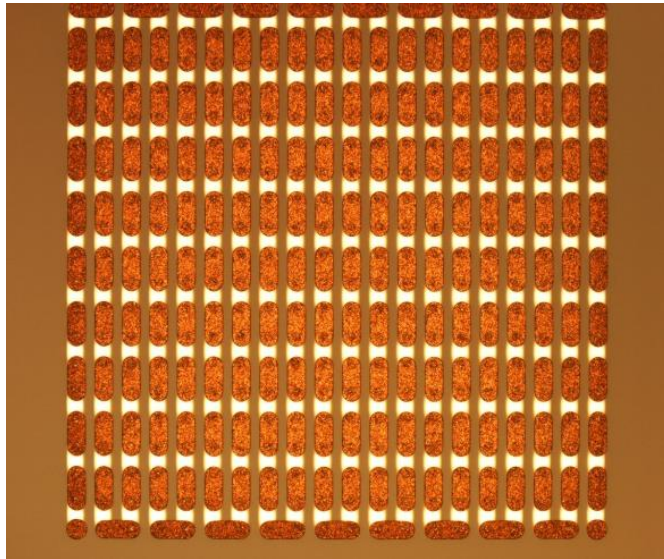


- Completed LC Network
- High Q inductance from 3D Solenoid inductor
- Capacitance achieved through MIM structure

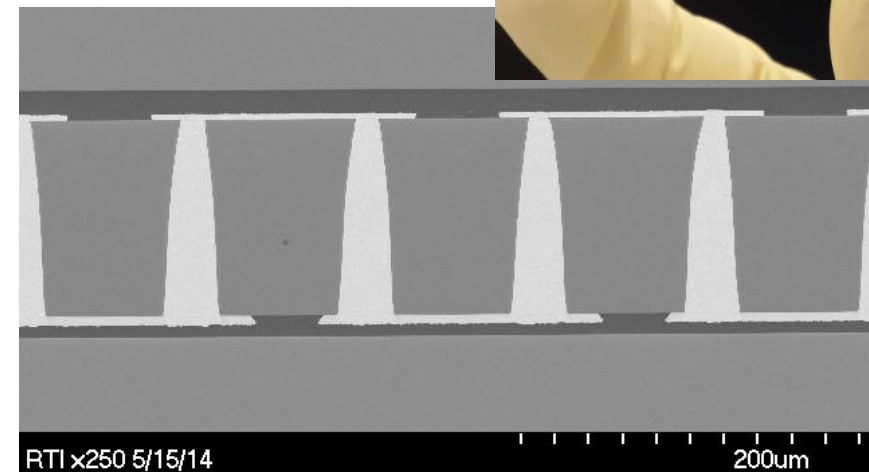
Electrical testing at ITRI shows that glass has better insertion loss vs standard Si, especially at high frequencies



Joint work with RTI demonstrated reliability of glass after 1000 thermal cycles



Daisy chain of Cu TGVs



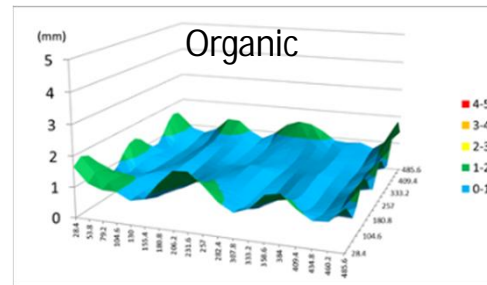
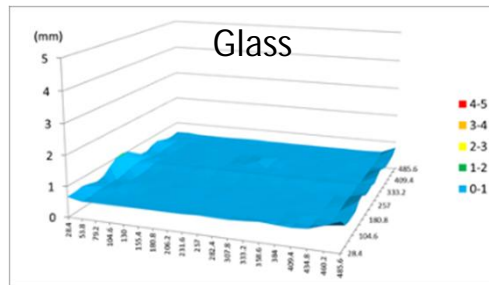
Profile of filled TGV



Electrical testing of TGV daisy chains: thermal cycling (-40 C to 125 C)

Wafer	CTE (ppm/°C)	No. of 20x20 arrays tested	No. of TGVs per chain	Pre-Thermal Cycling Yield of TGVs (%)	500 Thermal Cycles Yield of TGVs (%)	1000 Thermal Cycles Yield of TGVs (%)
SWG 3	3	8	400	100.00	100.00	100.00
SWG 8	8.5	8	400	100.00	100.00	100.00

Glass helps enable panel-level packaging, which potentially enables significant process savings for our customers

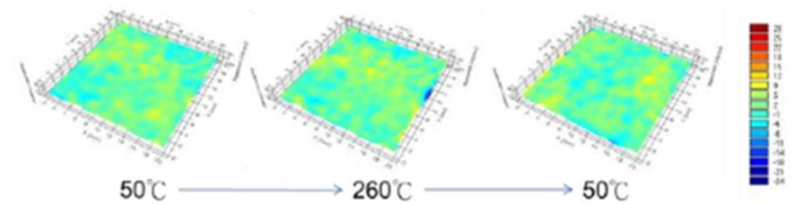
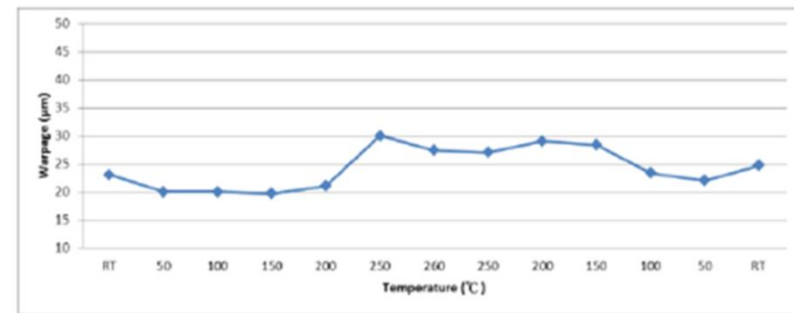


Left: Warpage measurement of glass substrate (2 build-up layers)

Right: Warpage measurement of organic substrate (2 build-up layers)



508 x 508mm glass panel

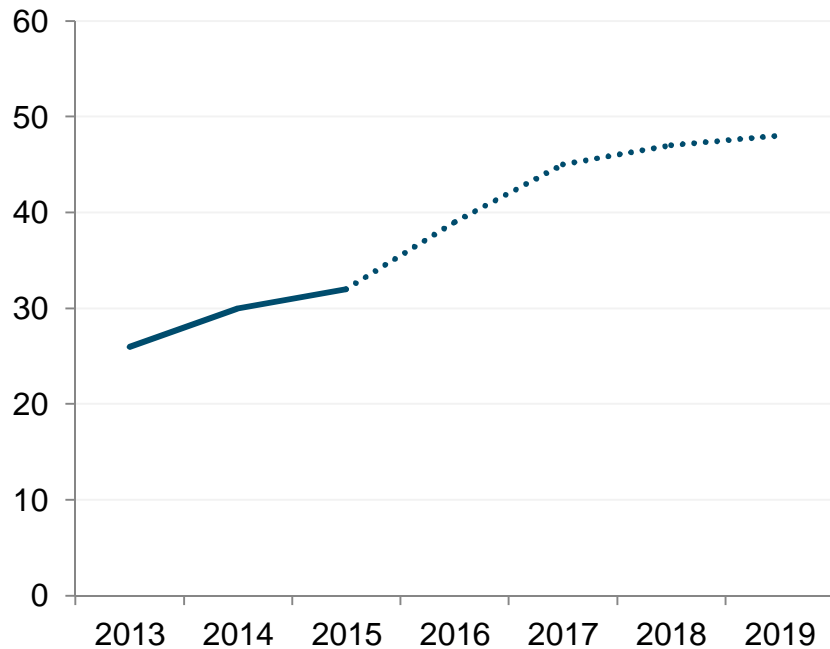


Targeted CTE of glass improves reliability of package (20x20mm)

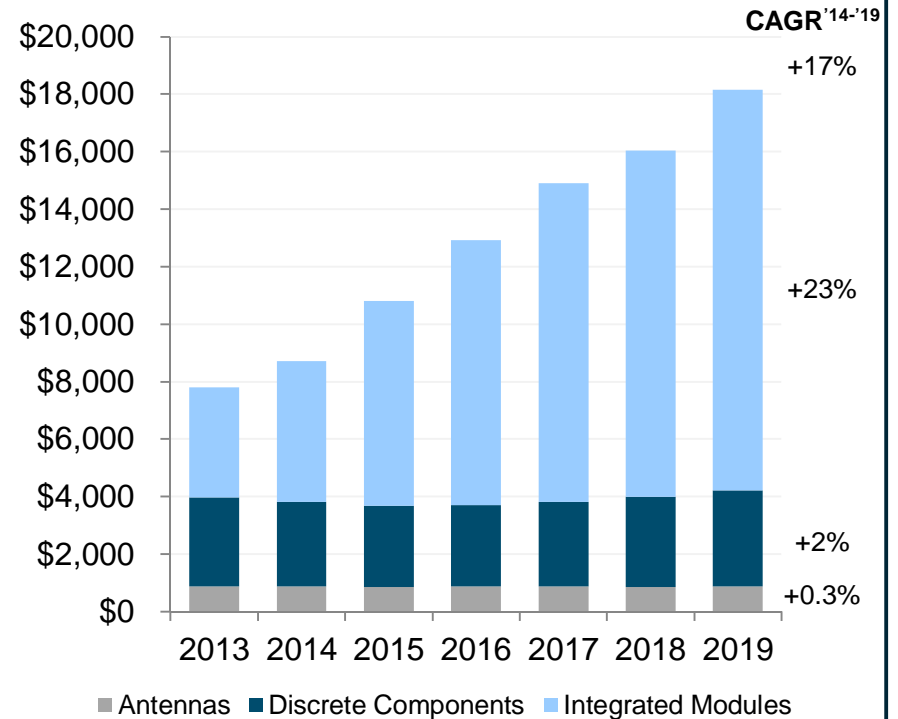
Source: YH Chen et al., Unimicron Technology Corp., Qualcomm Technologies, Inc., Corning Incorporated, "Low Cost Glass Interposer Development", 47th International Symposium on Microelectronics, San Diego 2014.

Glass is a good fit for the growing RF market

WW Frequency Bands



RF Front-End (RFFE) Market Size (\$M)



CARRIER	NETWORK	3G		4G LTE	
		BANDS	FREQUENCIES (MHz)	BANDS	FREQUENCIES (MHz)
VERIZON	CDMA	0, 1	850, 1900	2, 4, 13	1900, 1700 f, 700 c
AT&T	GSM/UMTS/HSPA+	2, 5	1900, 850	2, 4, 17	1900, 1700 abcde, 700 bc
T-MOBILE	GSM/UMTS/HSPA+	2, 4	1900, 1700/2100	2, 4, 12	1900, 1700 def, 700 a
SPRINT	CDMA	10, 1	800, 1900	25, 26, 41	1900 g, 850, 2500
US CELLULAR	CDMA	0, 1	850, 1900	5, 12	850, 700 ab

- RFFE market approaching \$20B in next few years
- Market growth driven by # bands
- Outlook flat for discrete devices, significant growth in integrated modules

Source: Mobile Experts, Corning Analysis

Key Takeaways

- Corning offers precision glass and precision holes for carrier and TGV applications; our unique offering translates into meaningful value for our customers
- We have demonstrated successful metallization of glass vias with several industry partners and are now working on real projects
- Electrical testing shows that glass has better insertion loss vs standard Si, especially at high frequencies; making it ideal for RF applications
- TGV is a reliable solution and can be offered in panel form factor, which potentially enables significant process savings for our customers

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